Deep Learning Based Object Detection

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Message from the Guest Editor

This Special Issue will cover the most recent technical advances in all deep learning-based object recognition aspects, including theoretical issues on deep learning, real-world applications, practical object detection systems, and originally designed databases. Both transfer learning or semi-supervised learning of deep learning are welcome. Reviews and surveys of the state-of-the-art in deep learning-based object detection are also welcome. Topics of interest for this Special Issue include, but are not limited to, the following topics:

- Image/video-based object detection using deep learning
- Sensor fusion for object detection using deep learning
- Transfer learning for object detection
- Online learning for object detection
- Active learning for object detection
- Semi-supervised learning for object detection
- Deep learning-based object detection for real-world applications
- Object detection systems
- New database for object detection
- Survey for deep learning-based object detection

Welcome to contribute.

Special Issue

Editor-in-Chief

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Message from the Editor-in-Chief

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